

Status: 04/07/2017

● = Click here for website
○ = Service is provided, but website is not available

Service	Tools	SDU	CAU	Acreo	WUT	UL	UT	KTU
Morphological characterization (nano/micro)	Phase-contrast Microscope	●		○				
	Interference Microscope	●		○				
	Optical and fluorescence microscope			○				●
	Optical microscope			○				●
	Orion Helium Ion Microscope (HIM)	○						
	Atomic Force Microscope (AFM)	●		○		○		●
	TEM, FIB-SEM			○		○	●	
	Scanning Electron Microscope (SEM), incl. EDX	●		○		○		●
Structural characterization	Fourier transform infrared spectroscope (FTIR)			○				●
	UV-VIS spectrometer			○				●
	RAMAN spectrometer			○			●	●
Measurement of thickness and optical properties	Elipsometer	●		○			●	○
	Laser elipsometer							●
Measurement of surface roughness	4 Point probestation			○				
	Thin film interferometer			○				○
	Profilometer	●		○				○
Characterizing of thin films (crystalline, polycrystalline and to some extent powder)	X-ray diffractometer			○			●	●
	XRF						●	
	X-ray photoelectron and ion scattering spectroscopy system							●
	X-ray energy dispersion spectrometer (EDX)							●
Chemical element analysis, chemical element distribution	X-Ray photoelectron spectroscopy							●
	Atomic Absorption Spectrometer							●
	Solar simulator	○						●
Electrical characterization of devices	Probe station/wafer tester	●		○				
	Probe station/chips tester			○				●
	Metrology-Manual probestation			○				
	Picoammeter/bias source							○
	Impedance analyzer							●
Analysis of PE performance	Wide Band Power Analyzer System				●			
	Power Analyzer				●			
Forward/Reverse/Blocking I-Vs characterization for diodes and transistors	Semiconductor Parameter Analyzer			○				
Thermal imaging for PE	Thermal Camera				●			
High temperature electrical characterization for power devices				○				
Discrete power devices in a plastic package and power module measurements (Static Characterizations for 5kV and 500 A)	Curve Tracer			○				
Discrete power devices in plastic package (Static Characterizations for 2 kV and 20 A)	Curve Tracer			○				

Status: 04/07/2017

Measurement of blocking voltage for 10 kV PiN diode	Curve Tracer		o		
Surge current measurement of power semiconductors for high amplitude and short pulse duration at high temperature	Surge current test equipment		o		
Double pulse test for switching performance of discrete SiC or Si power semiconductor devices up to 2.5 kV and 50 A	Dynamic characteriser for discrete devices		o		
Switching performance of power modules at different voltage and current ranges (1.2, 1.7, 3.3, and 4.5 kV and 50 - 500 A)	Dynamic characteriser for power modules (in delivery)		o		
Testing and troubleshooting for PE	Digital Phosphor Oscilloscope			•	
Testing of AC and DC PE converters	AC/DC Power Source			•	